



Combining Light and Electron Microscopy for Better Results

At DELMIC we develop high-end products that combine scanning electron microscopy with different forms of light microscopy and spectroscopy. The integrated design of our products delivers superior performance and user friendliness.

For the materials science, our SPARC platform offers unsurpassed sensitivity for cathodoluminescence detection. Application areas include geology, semiconductor materials, nano-photonics and plasmonics. Besides hyperspectral imaging, the SPARC platform has the capability to measure the angular cathodoluminescence emission profile which provides valuable additional information on the characteristics of your (nanoscale) system. The piezocontrolled optical alignment of the system gives it unprecedented sensitivity, enabling fast low-noise detection.

For the life sciences we offer two products, the Delphi and the SECOM. The SECOM is a high-end fluorescence microscope which can be retrofitted to an existing SEM. The Delphi is an all-in-one solution for correlative microscopy. While the SECOM is designed to be modular and allows you to take full advantage of the flexibility that is offered by the SEM of your choice, the Delphi is fully integrated CLEM solution with a very small footprint that is easy to use, install and maintain.

During this workshop we will introduce you to the DELMIC product range, followed by a live demonstration and a short hands-on session.